Form PTO-1449

IDS - 11/26/2003   Keith B. Stobie et al.

Serial No.:   Not Yet Assigned   Att'y Docket No.: 13768.459

Filing Date: November 26, 2003

For: DYNAMICALLY TUNABLE SOFTWARE TEST

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANT

U.S. Patent Documents

Examiner Initial*		Document Number	Issue Date	Name
ZW	1	5,513,315	04/30/96	Tierney et al.
ZW	2	5,548,718	08/20/96	Siegel et al.
ZW	3	5,774,725	06/30/98	Yadav et al.
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Other Documents
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ZW	9	P.D. Coward, "A Review of Software Testing", Information and Software Technology, Vol. 30, Issue 3, April 1988, pp. 189-98.

Examiner: /Zheng Wei/   Date Considered: 02/12/2007

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<u>ZW</u> 25   S.A. Walters, "Virtual Test Station (VTS)," 1993 IEEE.AIAA 12th Digital Avionics Systems Conference Proceedings, IEEE, October 1993, pp. 118-123.

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While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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